

Notice of References Cited	Application/Control No. 10/519,599		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner David Y. Chung		Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,636,282	10-2003	Ogawa et al.	349/58
*	B	US-7,178,963	02-2007	Ueda et al.	362/615
*	C	US-6,958,789	10-2005	Cueff et al.	349/61
*	D	US-2002/0113924	08-2002	Saito et al.	349/112
*	E	US-6,407,781	06-2002	Kitada, Takaaki	349/58
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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